

8Kx8 AutoStore nvSRAM

FEATURES

- 25, 35, 45, 55 ns Read Access & Write Cycle Time
- Unlimited Read/Write Endurance
- Automatic Non-volatile STORE on Power Loss
- Non-Volatile STORE Under Hardware or Software Control
- Automatic RECALL to SRAM on Power Up
- Unlimited RECALL Cycles
- 1 Million STORE Cycles
- 100-Year Non-volatile Data Retention
- Single 5V ± 10% Power Supply
- Commercial, Industrial, Military Temperatures
- 28-pin 330-mil SOIC, 300-mil PDIP, and 600-mil PDIP Packages (RoHS-Compliant)
- 28-Pin CDIP and LCC Military Packages

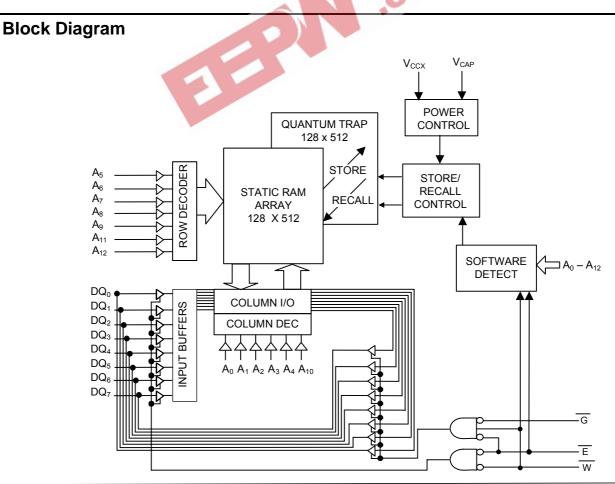
DESCRIPTION

The Simtek STK12C68 is a 64Kb fast static RAM with a non-volatile Quantum Trap storage element included with each memory cell.

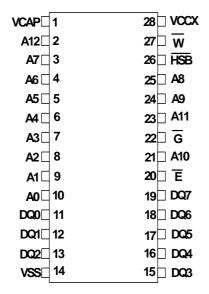
The SRAM provides the fast access & cycle times, ease of use and unlimited read & write endurance of a normal SRAM.

Data transfers automatically to the non-volatile storage cells when power loss is detected (the *STORE* operation). On power up, data is automatically restored to the SRAM (the *RECALL* operation). Both STORE and RECALL operations are also available under software control.

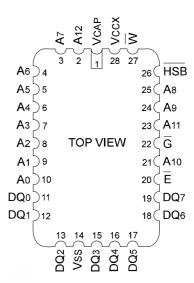
The Simtek nvSRAM is the first monolithic non-volatile memory to offer unlimited writes and reads. It is the highest performance, most reliable non-volatile memory available.



Packages







28-pin LCC

Pin Descriptions

	V33_ 1- 13_ D	
	28-pin SOIC 28-pin DIP	28-pin LCC
Pin Descrip	otions	Com
Pin Name	1/0	Description
A ₁₂ -A ₀	Input	Address: The 13 address inputs select one of 8,192 bytes in the nvSRAM array
DQ ₇ -DQ ₀	I/O	Data: Bi-directional 8-bit data bus for accessing the nvSRAM
Ē	Input	Chip Enable: The active low E input selects the device
W	Input	Write Enable: The active low \overline{W} enables data on the DQ pins to be written to the address location latched by the falling edge of \overline{E}
G	Input	Output Enable: The active low \overline{G} input enables the data output buffers during read cycles. De-asserting \overline{G} high caused the DQ pins to tri-state.
V _{CCX}	Power Supply	Power: 5.0V, +10%, -10%
HSB	I/O	Hardware Store Busy: When low this output indicates a Store is in progress. When pulled low external to the chip, it will initiate a nonvolatile STORE operation. A weak pull up resistor keeps this pin high if not connected. (Connection Optional).
V _{CAP}	Power Supply	AutoStore Capacitor: Supplies power to nvSRAM during power loss to store data from SRAM to nonvolatile storage elements.
V _{SS}	Power Supply	Ground

ABSOLUTE MAXIMUM RATINGS^a

Note a: Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only, and functional operation of the device at conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

DC CHARACTERISTICS

 $(V_{CC} = 5.0V \pm 10\%)^{e}$

SYMBOL	PARAMETER	СОММ	ERCIAL		ISTRIAL ITARY	UNITS	NOTES
		MIN	MAX	MIN	MAX		
I _{CC1} ^b	Average V _{CC} Current		85 75 65 		85 75 65 55	mA mA mA	t_{AVAV} = 25ns t_{AVAV} = 35ns t_{AVAV} = 45ns t_{AVAV} = 55ns
I _{CC2} ^c	Average V _{CC} Current during STORE		3		3	mA	All Inputs Don't Care, V _{CC} = max
I _{CC3} ^b	Average V _{CC} Current at t _{AVAV} = 200ns 5V, 25°C, Typical		10		10	mA	$\overline{W} \ge (V_{CC} - 0.2V)$ All Others Cycling, CMOS Levels
I _{CC4} ^c	Average V _{CAP} Current during AutoStore Cycle		2		2	mA	All Inputs Don't Care
I _{SB1} ^d	Average V _{CC} Current (Standby, Cycling TTL Input Levels)		27 24 20 		27 24 2 0 19	mA mA mA mA	$\begin{aligned} &t_{AVAV} = 25\text{ns}, \ \overline{E} \geq V_{IH} \\ &t_{AVAV} = 35\text{ns}, \ \overline{E} \geq V_{IH} \\ &t_{AVAV} = 45\text{ns}, \ \overline{E} \geq V_{IH} \\ &t_{AVAV} = 55\text{ns}, \ \overline{E} \geq V_{IH} \end{aligned}$
I _{SB2} ^d	V _{CC} Standby Current (Standby, Stable CMOS Input Levels)		1.5		2.5	mA	$\overline{E} \ge (V_{CC} - 0.2V)$ All Others $V_{IN} \le 0.2V$ or $\ge (V_{CC} - 0.2V)$
I _{ILK}	Input Leakage Current		±1		±1	μΑ	V_{CC} = max V_{IN} = V_{SS} to V_{CC}
l _{OLK}	Off-State Output Leakage Current		±5		±5	μΑ	V_{CC} = max V_{IN} = V_{SS} to V_{CC} , \overline{E} or $\overline{G} \ge V_{IH}$
V _{IH}	Input Logic "1" Voltage	2.2	V _{CC} + .5	2.2	V _{CC} + .5	V	All Inputs
V _{IL}	Input Logic "0" Voltage	V _{SS} 5	0.8	V _{SS} 5	0.8	V	All Inputs
V _{OH}	Output Logic "1" Voltage	2.4		2.4		V	I _{OUT} =-4mA except HSB
V _{OL}	Output Logic "0" Voltage		0.4		0.4	V	I _{OUT} = 8mA except HSB
V_{BL}	Logic "0" Voltage on HSB Output		0.4		0.4	V	I _{OUT} = 3mA
T _A	Operating Temperature	0	70	-40/-55	85/125	°C	

Note b: I_{CC_1} and I_{CC_3} are dependent on output loading and cycle rate. The specified values are obtained with outputs unloaded.

Note c: $\frac{1}{CC_2}$ and $\frac{1}{CC_4}$ are the average currents required for the duration of the respective STORE cycles (t_{STORE}).

Note d: $\overline{E} \ge V_{IH}$ will not produce standby current levels until any nonvolatile cycle in progress has timed out.

Note e: V_{CC} reference levels throughout this datasheet refer to V_{CCX} if that is where the power supply connection is made, or V_{CAP} if V_{CCX} is connected to ground.

AC TEST CONDITIONS

Input Pulse Levels	to 3V
Input Rise and Fall Times	≤ 5ns
Input and Output Timing Reference Levels	1.5V
Output Load See Figu	ure 1

CAPACITANCE^f $(T_A = 25^{\circ}C, f = 1.0MHz)$

SYMBOL	PARAMETER	MAX	UNITS	CONDITIONS
C _{IN}	Input Capacitance	8	pF	ΔV = 0 to 3V
C _{OUT}	Output Capacitance	7	pF	ΔV = 0 to 3V

Note f: These parameters are guaranteed but not tested.

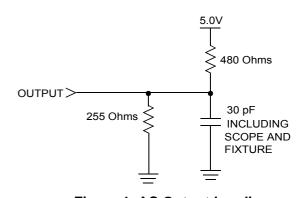


Figure 1. AC Output Loading



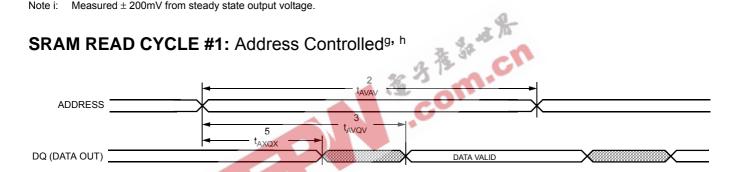
SRAM READ CYCLES #1 & #2

 $(V_{CC} = 5.0V \pm 10\%)^{e}$

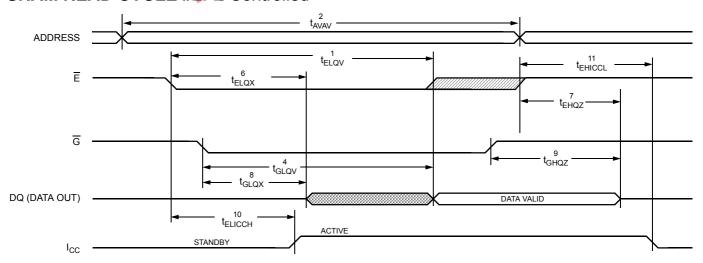
NO.	SYMBO	DLS	PARAMETER	STK12	C68-25	STK12	C68-35	STK12	C68-45	STK12	C68-55	UNITS
NO.	#1, #2	Alt.	PARAMETER	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	UNITS
1	t _{ELQV}	t _{ACS}	Chip Enable Access Time		25		35		45		55	ns
2	t _{AVAV} ^g	t _{RC}	Read Cycle Time	25		35		45		55		ns
3	t _{AVQV} h	t _{AA}	Address Access Time		25		35		45		55	ns
4	t_{GLQV}	t _{OE}	Output Enable to Data Valid		10		15		20		35	ns
5	t _{AXQX} h	t _{OH}	Output Hold after Address Change	5		5		5		5		ns
6	t _{ELQX}	t_{LZ}	Chip Enable to Output Active	5		5		5		5		ns
7	t _{EHQZ} i	t _{HZ}	Chip Disable to Output Inactive		10		10		12		12	ns
8	t_{GLQX}	t _{OLZ}	Output Enable to Output Active	0		0		0		0		ns
9	t _{GHQZ} i	t _{OHZ}	Output Disable to Output Inactive		10		10		12		12	ns
10	t _{ELICCH} f	t _{PA}	Chip Enable to Power Active	0		0		0		0		ns
11	t _{EHICCL} f	t _{PS}	Chip Disable to Power Standby		25		35		45		55	ns

Note g: \overline{W} and \overline{HSB} must be high during SRAM READ cycles. Note h: Device is continuously selected with \overline{E} and \overline{G} both low. Note i: Measured \pm 200mV from steady state output voltage.

SRAM READ CYCLE #1: Address Controlled^{9, h}



SRAM READ CYCLE #2: E Controlled⁹

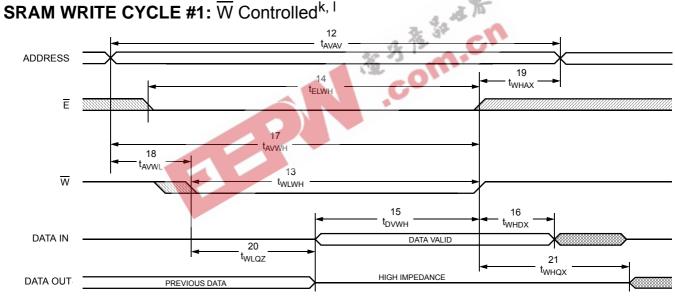




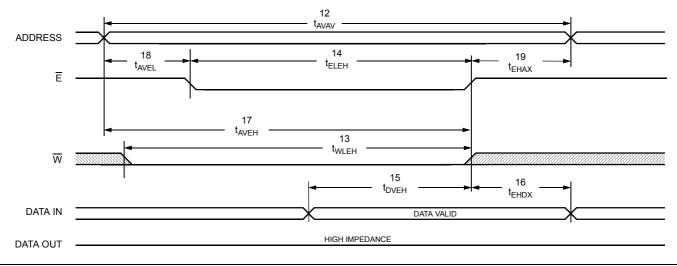
SRAM WRITE CYCLES #1 & #2

 $(V_{CC} = 5.0V \pm 10\%)^{e}$

NO		SYMBOLS		DADAMETED	STK12	C68-25	STK12	C68-35	STK12	C68-45	STK12	C68-55	LIMITO
NO.	#1	#2	Alt.	PARAMETER	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	UNITS
12	t _{AVAV}	t _{AVAV}	t _{WC}	Write Cycle Time	25		35		45		55		ns
13	t _{WLWH}	t _{WLEH}	t _{WP}	Write Pulse Width	20		25		30		45		ns
14	t _{ELWH}	t _{ELEH}	t _{CW}	Chip Enable to End of Write	20		25		30		45		ns
15	t _{DVWH}	t _{DVEH}	t _{DW}	Data Set-up to End of Write	10		12		15		25		ns
16	t _{WHDX}	t _{EHDX}	t _{DH}	Data Hold after End of Write	0		0		0		0		ns
17	t _{AVWH}	t _{AVEH}	t _{AW}	Address Set-up to End of Write	20		25		30		45		ns
18	t _{AVWL}	t _{AVEL}	t _{AS}	Address Set-up to Start of Write	0		0		0		0		ns
19	t _{WHAX}	t _{EHAX}	t _{WR}	Address Hold after End of Write	0		0		0		0		ns
20	t _{WLQZ} i, j		t _{WZ}	Write Enable to Output Disable		10		13		14		15	ns
21	t _{WHQX}		t _{OW}	Output Active after End of Write	5		5		5		5		ns



SRAM WRITE CYCLE #2: \overline{E} Controlled^{k, I}





HARDWARE MODE SELECTION

Ē	w	HSB	A ₁₂ - A ₀ (hex)	MODE	I/O	POWER	NOTES
Н	Х	Н	Х	Not Selected	Output High Z	Standby	
L	Н	Н	X	Read SRAM	Output Data	Active	0
L	L L		Х	Write SRAM	Input Data	Active	
Х	Х	L	Х	Nonvolatile STORE	Output High Z	I _{CC2}	m
L	н	н	0000 1555 0AAA 1FFF 10F0 0F0F	Read SRAM Read SRAM Read SRAM Read SRAM Read SRAM Nonvolatile <i>STORE</i>	Output Data Output Data Output Data Output Data Output Data Output Data Output High Z	Active	n, o
L	Н	Н	0000 1555 0AAA 1FFF 10F0 0F0E	Read SRAM Read SRAM Read SRAM Read SRAM Read SRAM Nonvolatile <i>RECALL</i>	Output Data Output Data Output Data Output Data Output Data Output Data Output High Z	Active	n, o

Note m: HSB STORE operation occurs only if an SRAM WRITE has been done since the last nonvolatile cycle. After the STORE (if any) completes, the part will go into standby mode, inhibiting all operations until HSB rises.

HARDWARE STORE CYCLE

$$(V_{CC} = 5.0V \pm 10\%)^{e}$$

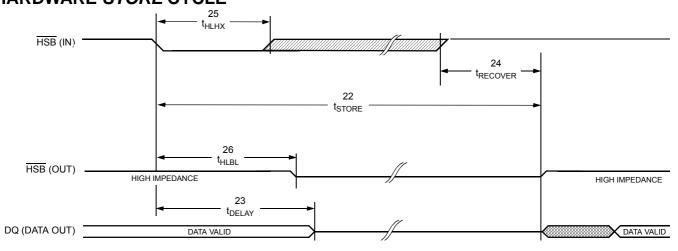
NO.	SYMI	BOLS	PARAMETER	STK1	2C68	UNITS	NOTES
	Standard	Alternate	PARAMETER	MIN	MAX	UNITS	
22	t _{STORE}	t _{HLHZ}	STORE Cycle Duration		10	ms	i, p
23	t _{DELAY}	t _{HLQZ}	Time Allowed to Complete SRAM Cycle	1		μs	i, q
24	t _{RECOVER}	t _{HHQX}	Hardware STORE High to Inhibit Off		700	ns	p, r
25	t _{HLHX}		Hardware STORE Pulse Width	15		ns	
26	t _{HLBL}		Hardware STORE Low to Store Busy		300	ns	

Note p: \overline{E} and \overline{G} low for output behavior.

Note q: \overline{E} and \overline{G} low and \overline{W} high for output behavior.

Note r: $t_{\mbox{\scriptsize RECOVER}}$ is only applicable after $t_{\mbox{\scriptsize STORE}}$ is complete.

HARDWARE STORE CYCLE





Note n: The six consecutive addresses must be in the order listed. W must be high during all six consecutive cycles to enable a nonvolatile cycle.

Note o: I/O state assumes $\overline{G} \le V_{IL}$. Activation of nonvolatile cycles does not depend on state of \overline{G} .

STK12C68 (SMD5962-94599) $(V_{CC} = 5.0V \pm 10\%)^{e}$

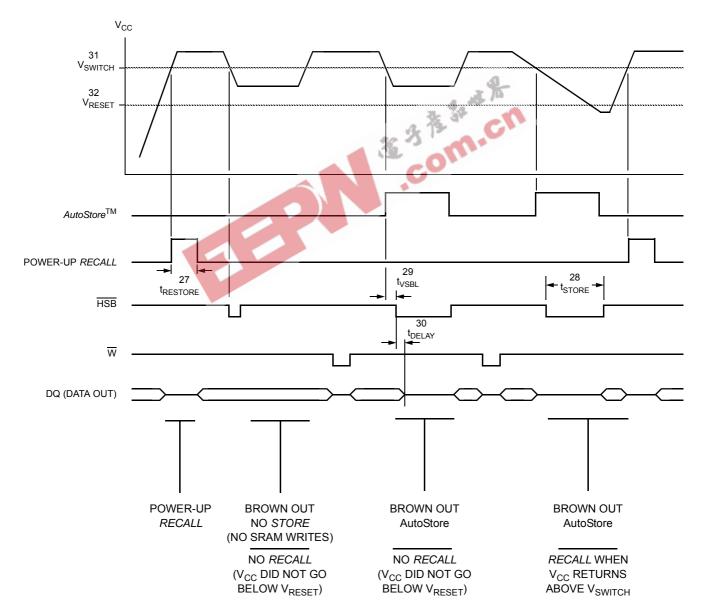
AutoStore / POWER-UP RECALL

NO.	SYMI	BOLS	PARAMETER	STK1	2C68	UNITS	NOTES
NO.	Standard	Alternate	FARAMETER	MIN	MAX	UNITS	
27	t _{RESTORE}		Power-up RECALL Duration		550	μs	S
28	t _{STORE}	t _{HLHZ}	STORE Cycle Duration		10	ms	p, q, t
29	t _{VSBL}		Low Voltage Trigger (V _{SWITCH}) to HSB Low		300	ns	ı
30	t _{DELAY}	t _{BLQZ}	Time Allowed to Complete SRAM Cycle	1		μs	р
31	V _{SWITCH}		Low Voltage Trigger Level	4.0	4.5	V	
32	V _{RESET}		Low Voltage Reset Level		3.9	V	

 $\frac{t_{RESTORE}}{\text{HSB}} \text{ starts from the time V}_{CC} \text{ rises above V}_{SWITCH}.$ $\text{HSB is asserted low for 1}_{\mu\text{S}} \text{ when V}_{CAP} \text{ drops through V}_{SWITCH}. \text{ If an SRAM WRITE has not taken place since the last nonvolatile cycle, } \overline{\text{HSB}}$

will be released and no STORE will take place.

AutoStore / POWER-UP RECALL





STK12C68 (SMD5962-94599) SOFTWARE-CONTROLLED STORE/RECALL CYCLE^V

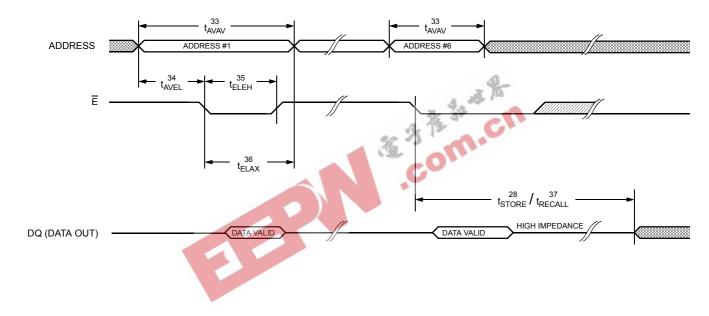
 $(V_{CC} = 5.0V \pm 10\%)^{e}$

NO.	SYMB	OLS	PARAMETER	STK12C68-25 STK12C68-35		STK12C68-45		STK12	C68-55	LIMITE	NOTES		
NO.	Standard	Alternate	PARAMETER	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	UNITS	NOTES
33	t _{AVAV}	t _{RC}	STORE/RECALL Initiation Cycle Time	25		35		45		55		ns	р
34	t _{AVEL}	t _{AS}	Address Set-up Time	0		0		0		0		ns	u
35	t _{ELEH}	t _{CW}	Clock Pulse Width	20		25		30		30		ns	u
36	t _{ELAX}		Address Hold Time	20		20		20		20		ns	u
37	t _{RECALL}		RECALL Duration		20		20		20		20	μs	

Note u: The software sequence is clocked with $\overline{\mathsf{E}}$ controlled READs.

The six consecutive addresses must be in the order listed in the Hardware Mode Selection Table: (0000, 1555, 0AAA, 1FFF, 10F0, 0F0F) for a STORE cycle or (0000, 1555, 0AAA, 1FFF, 10F0, 0F0E) for a RECALL cycle. W must be high during all six consecutive cycles.

SOFTWARE STORE/RECALL CYCLE: E Controlled





DEVICE OPERATION

The STK12C68 has two separate modes of operation: SRAM mode and nonvolatile mode. In SRAM mode, the memory operates as a standard fast static RAM. In nonvolatile mode, data is transferred from SRAM to Nonvolatile Elements (the *STORE* operation) or from Nonvolatile Elements to SRAM (the *RECALL* operation). In this mode SRAM functions are disabled.

NOISE CONSIDERATIONS

The STK12C68 is a high-speed memory and so must have a high-frequency bypass capacitor of approximately $0.1\mu F$ connected between V_{CAP} and V_{SS} , using leads and traces that are as short as possible. As with all high-speed CMOS ICs, normal careful routing of power, ground and signals will help prevent noise problems.

SRAM READ

The STK12C68 performs a READ cycle whenever \overline{E} and \overline{G} are low and \overline{W} and \overline{HSB} are high. The address specified on pins A_{0-12} determines which of the 8,192 data bytes will be accessed. When the READ is initiated by an address transition, the outputs will be valid after a delay of \underline{t}_{AVQV} (READ cycle #1). If the READ is initiated by \overline{E} or \overline{G} , the outputs will be valid at \underline{t}_{ELQV} or at \underline{t}_{GLQV} whichever is later (READ cycle #2). The data outputs will repeatedly respond to address changes within the \underline{t}_{AVQV} access time without the need for transitions on any control input pins, and will remain valid until another address change or until \overline{E} or \overline{G} is brought high, or \overline{W} or \overline{HSB} is brought low.

SRAM WRITE

A WRITE cycle is performed whenever \overline{E} and \overline{W} are low and \overline{HSB} is high. The address inputs must be stable prior to entering the WRITE cycle and must remain stable until either \overline{E} or \overline{W} goes high at the end of the cycle. The data on the common I/O pins DQ₀₋₇ will be written into the memory if it is valid t_{DVWH} before the end of a \overline{W} controlled WRITE or t_{DVEH} before the end of an \overline{E} controlled WRITE.

It is recommended that \overline{G} be kept high during the entire WRITE cycle to avoid data bus contention on common I/O lines. If \overline{G} is left low, internal circuitry will turn off the output buffers t_{WLOZ} after \overline{W} goes low.

POWER-UP RECALL

During power up, or after any low-power condition ($V_{CAP} < V_{RESET}$), an internal *RECALL* request will be latched. When V_{CAP} once again exceeds the sense voltage of V_{SWITCH} , a *RECALL* cycle will automatically be initiated and will take $t_{RESTORE}$ to complete.

If the STK12C68 is in a WRITE state at the end of power-up *RECALL*, the SRAM data will be corrupted. To help avoid this situation, a 10K Ohm resistor should be connected either between \overline{W} and system V_{CC} or between \overline{E} and system V_{CC} .

SOFTWARE NONVOLATILE STORE

The STK12C68 software *STORE* cycle is initiated by executing sequential \overline{E} controlled READ cycles from six specific address locations. During the *STORE* cycle an erase of the previous nonvolatile data is first performed, followed by a program of the nonvolatile elements. The program operation copies the SRAM data into nonvolatile memory. Once a *STORE* cycle is initiated, further input and output are disabled until the cycle is completed.

Because a sequence of READs from specific addresses is used for *STORE* initiation, it is important that no other READ or WRITE accesses intervene in the sequence, or the sequence will be aborted and no *STORE* or *RECALL* will take place.

To initiate the software *STORE* cycle, the following READ sequence must be performed:

1.	Read address	0000 (hex)	Valid READ
2.	Read address	1555 (hex)	Valid READ
3.	Read address	0AAA (hex)	Valid READ
4.	Read address	1FFF (hex)	Valid READ
5.	Read address	10F0 (hex)	Valid READ
6.	Read address	0F0F (hex)	Initiate STORE cycle

The software sequence must be clocked with \overline{E} controlled READs.

Once the sixth address in the sequence has been entered, the *STORE* cycle will commence and the chip will be disabled. It is important that READ cycles and not WRITE cycles be used in the sequence, although it is not necessary that \overline{G} be low for the sequence to be valid. After the t_{STORE} cycle time has been fulfilled, the SRAM will again be activated for READ and WRITE operation.



SOFTWARE NONVOLATILE RECALL

A software *RECALL* cycle is initiated with a sequence of READ operations in a manner similar to the software *STORE* initiation. To initiate the *RECALL* cycle, the following sequence of \overline{E} controlled READ operations must be performed:

1.	Read address	0000 (hex)	Valid READ
2.	Read address	1555 (hex)	Valid READ
3.	Read address	0AAA (hex)	Valid READ
4.	Read address	1FFF (hex)	Valid READ
5.	Read address	10F0 (hex)	Valid READ
6.	Read address	0F0E (hex)	Initiate RECALL cycle

Internally, RECALL is a two-step procedure. First, the SRAM data is cleared, and second, the nonvolatile information is transferred into the SRAM cells. After the t_{RECALL} cycle time the SRAM will once again be ready for READ and WRITE operations. The RECALL operation in no way alters the data in the Nonvolatile Elements. The nonvolatile data can be recalled an unlimited number of times.

AutoStore OPERATION

The STK12C68 can be powered in one of three modes.

During normal AutoStore operation, the STK12C68 will draw current from V_{CCX} to charge a capacitor connected to the V_{CAP} pin. This stored charge will be used by the chip to perform a single *STORE* operation. After power up, when the voltage on the V_{CAP} pin drops below V_{SWITCH} , the part will automatically disconnect the V_{CAP} pin from V_{CCX} and initiate a *STORE* operation.

Figure 2 shows the proper connection of capacitors for automatic store operation. A charge storage

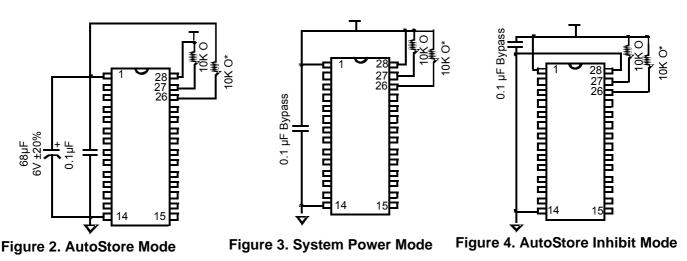
capacitor having a capacity of between $68\mu F$ and $220\mu F$ ($\pm~20\%$) rated at 6V should be provided.

In system power mode (Figure 3), both V_{CCX} and V_{CAP} are connected to the + 5V power supply without the $68\mu\text{F}$ capacitor. In this mode the AutoStore function of the STK12C68 will operate on the stored system charge as power goes down. The user must, however, guarantee that V_{CCX} does not drop below 3.6V during the 10ms STORE cycle.

If an automatic *STORE* on power loss is not required, then V_{CCX} can be tied to ground and + 5V applied to V_{CAP} (Figure 4). This is the AutoStore Inhibit mode, in which the AutoStore function is disabled. If the STK12C68 is operated in this configuration, references to V_{CCX} should be changed to V_{CAP} throughout this data sheet. In this mode, *STORE* operations may be triggered through software control or the $\overline{\text{HSB}}$ pin. It is not permissible to change between these three options "on the fly."

In order to prevent unneeded *STORE* operations, automatic *STORE*s as well as those initiated by externally driving HSB low will be ignored unless at least one WRITE operation has taken place since the most recent *STORE* or *RECALL* cycle. Software initiated *STORE* cycles are performed regardless of whether a WRITE operation has taken place. An optional pull-up resistor is shown connected to HSB. This can be used to signal the system that the AutoStore cycle is in progress.

If the power supply drops faster than 20 $\mu s/volt$ before V_{CCX} reaches V_{SWITCH} , then a 2.2 ohm resistor should be inserted between V_{CCX} and the system supply to avoid momentary excess of current between Vccx and Vcap.





HSB OPERATION

The STK12C68 provides the HSB pin for controlling and acknowledging the *STORE* operations. The HSB pin is used to request a hardware *STORE* cycle. When the HSB pin is driven low, the STK12C68 will conditionally initiate a *STORE* operation after to the SRAM took place since the last *STORE* or *RECALL* cycle. The HSB pin acts as an open drain driver that is internally driven low to indicate a busy condition while the *STORE* (initiated by any means) is in progress.

SRAM READ and WRITE operations that are in progress when HSB is driven low by any means are given time to complete before the *STORE* operation is initiated. After HSB goes low, the STK12C68 will continue SRAM operations for t_{DELAY}, During t_{DELAY}, multiple SRAM READ operations may take place. If a WRITE is in progress when HSB is pulled low it will be allowed a time, t_{DELAY}, to complete. However, any SRAM WRITE cycles requested after HSB goes low will be inhibited until HSB returns high.

The $\overline{\text{HSB}}$ pin can be used to synchronize multiple STK12C68s while using a single larger capacitor. To operate in this mode the $\overline{\text{HSB}}$ pin should be connected together to the $\overline{\text{HSB}}$ pins from the other STK12C68s. An external pull-up resistor to + 5V is required since $\overline{\text{HSB}}$ acts as an open drain pull down. The V_{CAP} pins from the other STK12C68 parts can be tied together and share a single capacitor. The capacitor size must be scaled by the number of devices connected to it. When any one of the STK12C68s detects a power loss and asserts $\overline{\text{HSB}}$, the common $\overline{\text{HSB}}$ pin will cause all parts to request a *STORE* cycle (a *STORE* will take place in those STK12C68s that have been written since the last nonvolatile cycle).

During any *STORE* operation, regardless of how it was <u>initiated</u>, the STK12C68 will continue to drive the HSB pin low, releasing it only when the *STORE* is complete. Upon completion of the *STORE* operation the STK12C68 will remain disabled until the HSB pin returns high.

If HSB is not used, it should be left unconnected.

PREVENTING STORES

The STORE function can be disabled on the fly by holding HSB high with a driver capable of sourcing 30mA at a V_{OH} of at least 2.2V, as it will have to overpower the internal pull-down device that drives HSB low for 20 μ s at the onset of a STORE. When the STK12C68 is connected for AutoStore operation (system V_{CC} connected to V_{CCX} and a 68μ F capacitor on V_{CAP}) and V_{CC} crosses V_{SWITCH} on the way down, the STK12C68 will attempt to pull HSB low; if HSB doesn't actually get below V_{IL} , the part will stop trying to pull HSB low and abort the STORE attempt.

HARDWARE PROTECT

The STK12C68 offers hardware protection against inadvertent STORE operation and SRAM WRITES during low-voltage conditions. When $V_{CAP} < V_{SWITCH}$, all externally initiated STORE operations and SRAM WRITES are inhibited.

AutoStore can be completely disabled by tying V_{CCX} to ground and applying + 5V to V_{CAP} . This is the AutoStore Inhibit mode; in this mode, *STORE*s are only initiated by explicit request using either the software sequence or the HSB pin.

LOW AVERAGE ACTIVE POWER

The STK12C68 draws significantly less current when it is cycled at times longer than 50ns. Figure 5 shows the relationship between $I_{\rm CC}$ and READ cycle time. Worst-case current consumption is shown for both CMOS and TTL input levels (commercial temperature range, $V_{\rm CC}$ = 5.5V, 100% duty cycle on chip enable). Figure 6 shows the same relationship for WRITE cycles. If the chip enable duty cycle is less than 100%, only standby current is drawn when the chip is disabled. The overall average current drawn by the STK12C68 depends on the following items: 1) CMOS vs. TTL input levels; 2) the duty cycle of chip enable; 3) the overall cycle rate for accesses; 4) the ratio of READs to WRITEs; 5) the operating temperature; 6) the $V_{\rm CC}$ level; and 7) I/O loading.



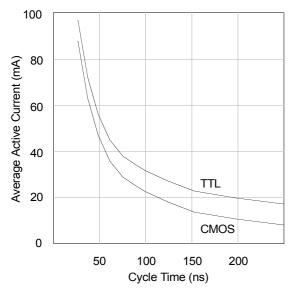


Figure 5: I_{cc} (max) Reads

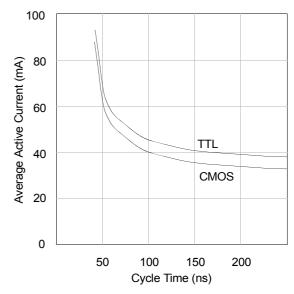
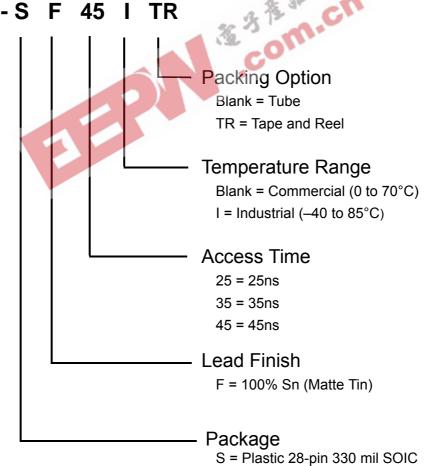


Figure 6: I_{cc} (max) Writes

Commercial and Industrial Ordering Information STK12C68 - S F 45 I TR

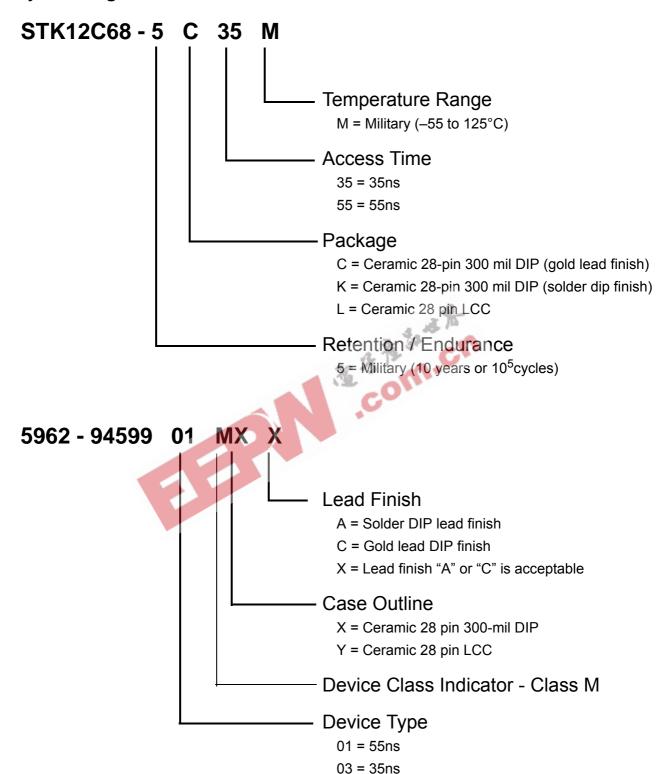




W = Plastic 28-pin 600 mil DIP P = Plastic 28-pin 300 mil DIP C = Ceramic 28-pin 300 mil DIP

L = Ceramic 28-pin LLC

Military Ordering Information





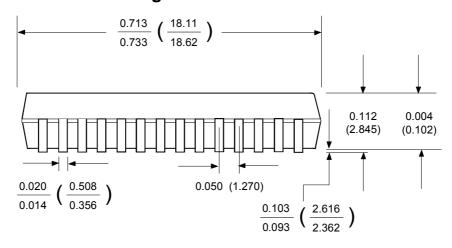
Ordering Information

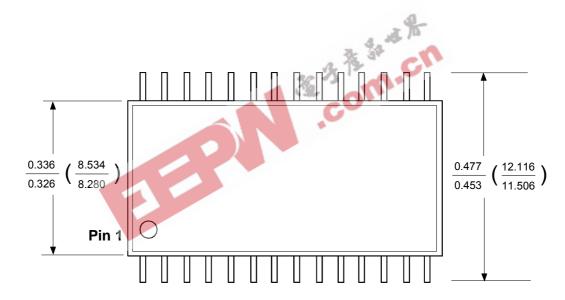
Part Number	Description	Temperature
STK12C68-C35	5V 8Kx8 AutoStore nvSRAM CDIP28-300	Commercial
STK12C68-C45	5V 8Kx8 AutoStore nvSRAM CDIP28-300	Commercial
STK12C68-L35	5V 8Kx8 AutoStore nvSRAM LCC28	Commercial
STK12C68-L45	5V 8Kx8 AutoStore nvSRAM LCC28	Commercial
STK12C68-PF25	5V 8Kx8 AutoStore nvSRAM PDIP28-600	Commercial
STK12C68-PF45	5V 8Kx8 AutoStore nvSRAM PDIP28-600	Commercial
STK12C68-SF25	5V 8Kx8 AutoStore nvSRAM SOP28-330	Commercial
STK12C68-SF25TR	5V 8Kx8 AutoStore nvSRAM SOP28-330	Commercial
STK12C68-SF45	5V 8Kx8 AutoStore nvSRAM SOP28-330	Commercial
STK12C68-SF45TR	5V 8Kx8 AutoStore nvSRAM SOP28-330	Commercial
STK12C68-WF25	5V 8Kx8 AutoStore nvSRAM PDIP28-600	Commercial
STK12C68-WF45	5V 8Kx8 AutoStore nvSRAM PDIP28-600	Commercial
STK12C68-C35I	5V 8Kx8 AutoStore nvSRAM CDIP28-300	Industrial
STK12C68-C45I	5V 8Kx8 AutoStore nvSRAM CDIP28-300	Industrial
STK12C68-L35I	5V 8Kx8 AutoStore nvSRAM LCC28	Industrial
STK12C68-L45I	5V 8Kx8 AutoStore nvSRAM LCC28	Industrial
STK12C68-PF25I	5V 8Kx8 AutoStore nvSRAM PDIP28-600	Industrial
STK12C68-PF45I	5V 8Kx8 AutoStore nvSRAM_PDIP28-600	Industrial
STK12C68-SF25I	5V 8Kx8 AutoStore nvSRAM SOP28-330	Industrial
STK12C68-SF25ITR	5V 8Kx8 AutoStore nvSRAM SOP28-330	Industrial
STK12C68-SF45I	5V 8Kx8 AutoStore nvSRAM SOP28-330	Industrial
STK12C68-SF45ITR	5V 8Kx8 AutoStore nvSRAM SOP28-330	Industrial
STK12C68-WF25I	5V 8Kx8 AutoStore nvSRAM PDIP28-600	Industrial
STK12C68-WF45I	5V 8Kx8 AutoStore nvSRAM PDIP28-600	Industrial
SMD5962-9459901MXA	5V 8Kx8 AutoStore nvSRAM CDIP28-300	Military
SMD5962-9459901MXC	5V 8Kx8 AutoStore nvSRAM CDIP28-300	Military
SMD5962-9459901MXX	5V 8Kx8 AutoStore nvSRAM CDIP28-300	Military
SMD5962-9459901MYA	5V 8Kx8 AutoStore nvSRAM LCC28	Military
SMD5962-9459901MYX	5V 8Kx8 AutoStore nvSRAM LCC28	Military
SMD5962-9459903MXA	5V 8Kx8 AutoStore nvSRAM CDIP28-300	Military
SMD5962-9459903MXC	5V 8Kx8 AutoStore nvSRAM CDIP28-300	Military
SMD5962-9459903MXX	5V 8Kx8 AutoStore nvSRAM CDIP28-300	Military
SMD5962-9459903MYA	5V 8Kx8 AutoStore nvSRAM LCC28	Military
SMD5962-9459903MYX	5V 8Kx8 AutoStore nvSRAM LCC28	Military
STK12C68-5C35M	5V 8Kx8 AutoStore nvSRAM CDIP28-300	Military
STK12C68-5C55M	5V 8Kx8 AutoStore nvSRAM CDIP28-300	Military
STK12C68-5K35M	5V 8Kx8 AutoStore nvSRAM CDIP28-300	Military
STK12C68-5K55M	5V 8Kx8 AutoStore nvSRAM CDIP28-300	Military
STK12C68-5L35M	5V 8Kx8 AutoStore nvSRAM LCC28	Military
STK12C68-5L55M	5V 8Kx8 AutoStore nvSRAM LCC28	Military

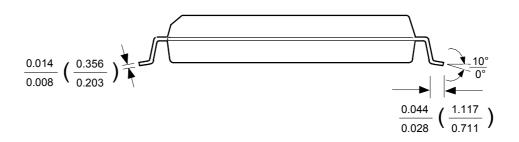


Package Diagrams

28-Lead, 330 mil SOIC Gull Wing





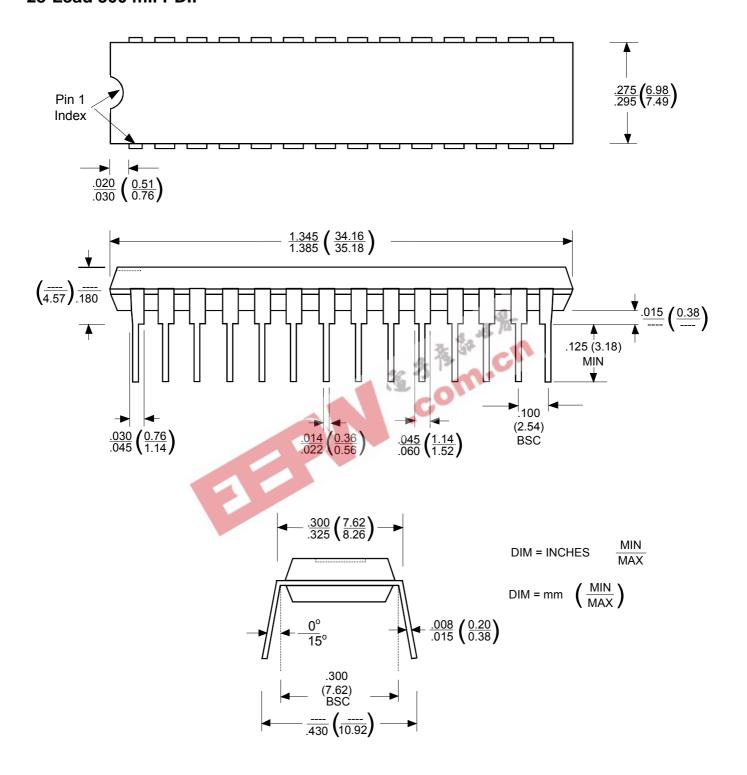


DIM = INCHES
$$\frac{MIN}{MAX}$$

DIM = mm $\left(\frac{MIN}{MAX}\right)$

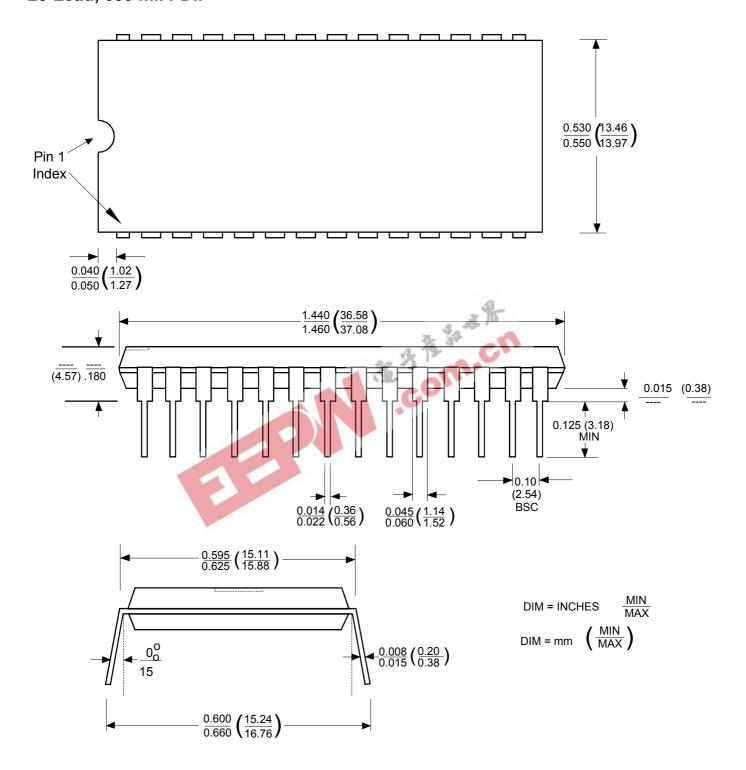


28-Lead 300 mil PDIP



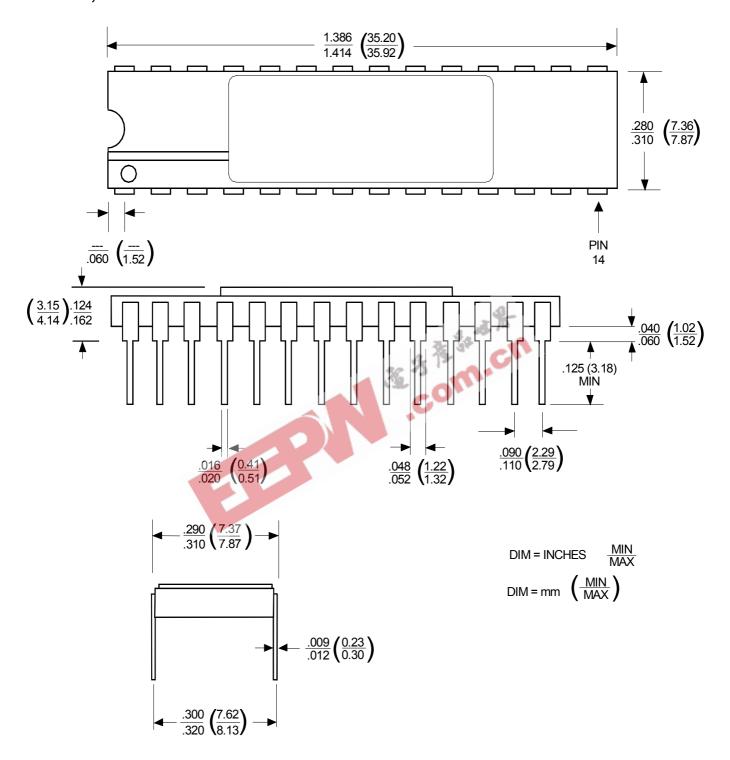


28-Lead, 600 mil PDIP



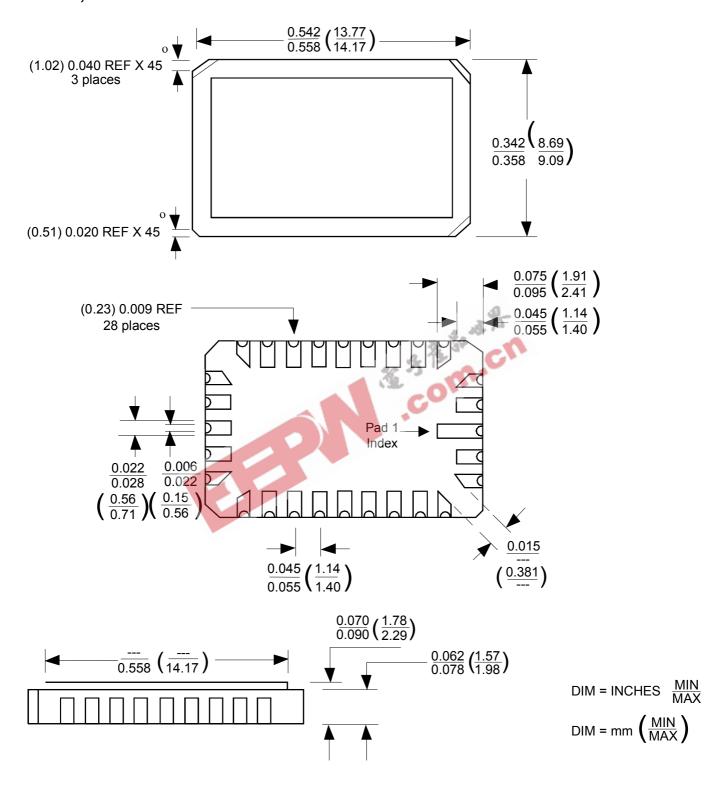


28-Lead, 300 mil Side Braze DIL





28-Pad, 350 mil Ceramic LCC





Document Revision History

Revision	Date	Summary
0.0	December 2002	Combined commercial, industrial and military data sheets. Removed 20 nsec device.
0.1	January 2003	Added 35ns SMD to order information
0.2	July 2003	Added "28 - SOIC" label to page 1 pinout drawing
0.3	September 2003	Added lead-free lead finish
0.4	October 2003	Restored "W" 600 mil DIP package to ordering information
0.5	March 2006	Removed Commercial 35 ns and leaded lead finish, Removed Military 45ns device
0.6	August 2006	Reformat SMD Ordering Information to SDDC Part Number Format
0.7	February 2007	Add Fast Power-Down Slew Rate Information
		Restore Comm/Ind C & L Package Options Add Tape Reel Ordering Options Add Product Ordering Code Listing Add Package Outline Drawings Reformat Entire Document

SIMTEK STK12C68 Datasheet, February 2007

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